



F100354

Low Power 8-Bit Register with Cut-Off Drivers

General Description

The F100354 contains eight D-Type edge triggered, master/slave flip-flops with individual inputs (D_n), true outputs (Q_n), a clock input (CP), an output enable pin (\overline{OEN}), and a common clock enable pin (\overline{CEN}). Data enters the master when CP is LOW and transfers to the slave when CP goes HIGH. When the \overline{CEN} input goes HIGH it overrides all other inputs, disables the clock, and the Q outputs maintain the last state.

A Q output follows its D input when the \overline{OEN} pin is LOW. A HIGH on \overline{OEN} holds the outputs in a cut-off state. The cut-off state is designed to be more negative than a normal ECL LOW level. This allows the output emitter-followers to turn off when the termination supply is $-2.0V$, presenting a high

impedance to the data bus. This high impedance reduces termination power and prevents loss of low state noise margin when several loads share the bus.

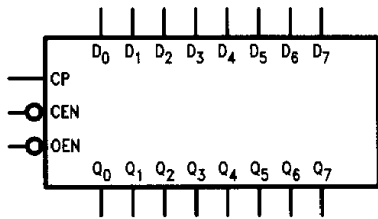
The F100354 outputs are designed to drive a doubly terminated 50Ω transmission line (25Ω load impedance). All inputs have $50\text{ k}\Omega$ pull-down resistors.

Features

- Cut-off drivers
- Drives 25Ω load
- Low power operation
- 2000V ESD protection
- Voltage compensated operating range = $-4.2V$ to $-5.7V$

Ordering Code: See Section 8

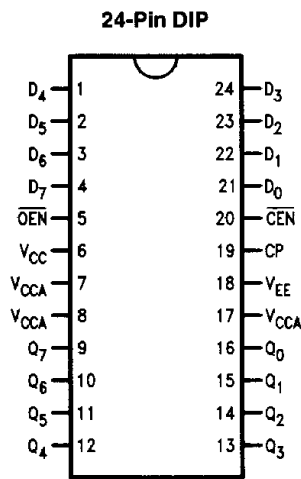
Logic Symbol



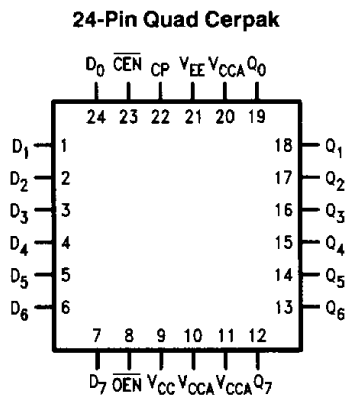
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Pin Names	Description
D_0 - D_7	Data Inputs
\overline{CEN}	Clock Enable Input
CP	Clock Input (Active Rising Edge)
\overline{OEN}	Output Enable Input
Q_0 - Q_7	Data Outputs

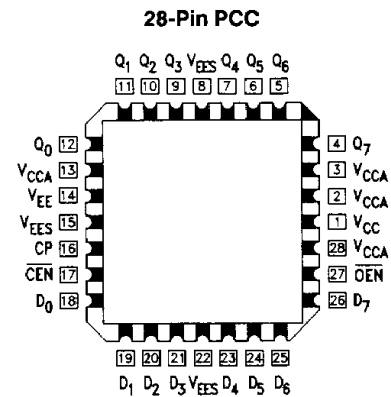
Connection Diagrams



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Absolute Maximum Ratings

Above which the useful life may be impaired. (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Storage Temperature (T_{STG})	-65°C to +150°C
Maximum Junction Temperature (T_J)	
Ceramic	+175°C
Plastic	+150°C
V_{EE} Pin Potential to Ground Pin	-7.0V to +0.5V
Input Voltage (DC)	V_{EE} to +0.5V
Output Current (DC Output HIGH)	-100 mA
ESD (Note 2)	≥2000V

Commercial Version

DC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = 0^\circ C$ to $+85^\circ C$ (Note 3)

Symbol	Parameter	Min	Typ	Max	Units	Conditions
V_{OH}	Output HIGH Voltage	-1025	-955	-870	mV	$V_{IN} = V_{IH} (Max)$ or $V_{IL} (Min)$ Loading with 25Ω to -2.0V
V_{OL}	Output LOW Voltage	-1830	-1705	-1620		
V_{OHC}	Output HIGH Voltage	-1035			mV	$V_{IN} = V_{IH} (Min)$ or $V_{IL} (Max)$ Loading with 25Ω to -2.0V
V_{OLC}	Output LOW Voltage			-1610		
V_{OLZ}	Cutoff LOW Voltage			-1950	mV	$V_{IN} = V_{IH} (Min)$ or $V_{IL} (Max)$ $\overline{OEN} = HIGH$
V_{IH}	Input HIGH Voltage	-1165		-870	mV	Guaranteed HIGH Signal for All Inputs
V_{IL}	Input LOW Voltage	-1830		-1475	mV	Guaranteed LOW Signal for All Inputs
I_{IL}	Input LOW Current	0.50			μA	$V_{IN} = V_{IL} (Min)$
I_{IH}	Input HIGH Current			240	μA	$V_{IN} = V_{IH} (Max)$
I_{EE}	Power Supply Current	-202 -209		-105 -105	mA	Inputs Open $V_{EE} = -4.2V$ to $-4.8V$ $V_{EE} = -4.2V$ to $-5.7V$

Note 1: Absolute maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: ESD testing conforms to MIL-STD-883, Method 3015.

Note 3: The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

Commercial Version (Continued)**Ceramic Dual-In-Line Package AC Electrical Characteristics** $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
f_{Max}	Toggle Frequency	250		250		250		MHz	Figures 1 and 4
t_{PLH} t_{PHL}	Propagation Delay CP to Output	1.40	3.00	1.40	3.00	1.50	3.10	ns	Figures 1 and 4 (Note 1)
t_{PZH} t_{PHZ}	Propagation Delay \overline{OEN} to Output	1.60	4.20	1.60	4.20	1.60	4.20	ns	Figures 3 and 7 (Note 1)
t_{TLH} t_{THL}	Transition Time 20% to 80%, 80% to 20%	0.45	2.00	0.45	2.00	0.45	2.00	ns	Figures 1 and 4
t_s	Setup Time D_n \overline{CEN} (Disable Time) \overline{CEN} (Release Time)	1.10 0.40 1.10		1.10 0.40 1.10		1.10 0.40 1.10		ns	Figures 2 and 5
t_h	Hold Time D_n	0.10		0.10		0.10		ns	Figures 1 and 6
$t_{pw(H)}$	Pulse Width High CP	2.00		2.00		2.00		ns	Figures 1 and 4

Note 1: The propagation delay specified is for single output switching. Delays may vary up to 300 ps with multiple outputs switching.

PCC and Cerpak AC Electrical Characteristics $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
f_{Max}	Toggle Frequency	250		250		250		MHz	Figures 1 and 4
t_{PLH} t_{PHL}	Propagation Delay CP to Output	1.40	2.80	1.40	2.80	1.50	2.90	ns	Figures 1 and 4 (Note 2)
t_{PZH} t_{PHZ}	Propagation Delay \overline{OEN} to Output	1.60	4.00	1.60	4.00	1.60	4.00	ns	Figures 3 and 7 (Note 2)
t_{TLH} t_{THL}	Transition Time 20% to 80%, 80% to 20%	0.45	1.90	0.45	1.90	0.45	1.90	ns	Figures 1 and 4
t_s	Setup Time D_n \overline{CEN} (Disable Time) \overline{CEN} (Release Time)	1.00 0.30 1.00		1.00 0.30 1.00		1.00 0.30 1.00		ns	Figures 2 and 5
t_h	Hold Time D_n	0.00		0.00		0.00		ns	Figures 1 and 6
$t_{pw(H)}$	Pulse Width High CP	2.00		2.00		2.00		ns	Figures 1 and 4
$t_{s, G-G}$	Skew, Gate to Gate		TBD		TBD		TBD	ps	PCC Only (Note 1)

Note 1: Gate to gate skew is defined as the difference in propagation delays between each of the outputs.

Note 2: The propagation delay specified is for single output switching. Delays may vary up to 300 ps with multiple outputs switching.

Military Version—Preliminary

DC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = -55^{\circ}C$ to $+125^{\circ}C$

Symbol	Parameter	Min	Max	Units	T_C	Conditions	Notes	
V_{OH}	Output HIGH Voltage	-1025	-870	mV	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH} (Max)$ or $V_{IL} (Min)$	Loading with 25Ω to $-2.0V$	1, 2, 3
		-1085	-870	mV	$-55^{\circ}C$			
V_{OL}	Output LOW Voltage	-1830	-1620	mV	$0^{\circ}C$ to $+125^{\circ}C$			
		-1830	-1555	mV	$-55^{\circ}C$			
V_{OHC}	Output HIGH Voltage	-1035		mV	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH} (Min)$ or $V_{IL} (Max)$	Loading with 25Ω to $-2.0V$	1, 2, 3
		-1085		mV	$-55^{\circ}C$			
V_{OLC}	Output LOW Voltage		-1610	mV	$0^{\circ}C$ to $+125^{\circ}C$			
			-1555	mV	$-55^{\circ}C$			
V_{OLZ}	Cutoff LOW Voltage		-1950	mV	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH} (Min)$ or $V_{IL} (Max)$	$\overline{OEN} = HIGH$	1, 2, 3
			-1850	mV	$-55^{\circ}C$			
V_{IH}	Input HIGH Voltage	-1165	-870	mV	$-55^{\circ}C$ to $+125^{\circ}C$	Guaranteed HIGH Signal for All Inputs	1, 2, 3, 4	
V_{IL}	Input LOW Voltage	-1830	-1475	mV	$-55^{\circ}C$ to $+125^{\circ}C$	Guaranteed LOW Signal for All Inputs	1, 2, 3, 4	
I_{IL}	Input LOW Current	0.50		μA	$-55^{\circ}C$ to $+125^{\circ}$	$V_{EE} = -4.2V$ $V_{IN} = V_{IL} (Min)$	1, 2, 3	
I_{IH}	Input HIGH Current		240	μA	$0^{\circ}C$ to $+125^{\circ}C$	$V_{EE} = -5.7V$ $V_{IN} = V_{IH} (Max)$	1, 2, 3	
			340	μA	$-55^{\circ}C$			
I_{EE}	Power Supply Current	-215 -225	-85 -85	mA	$-55^{\circ}C$ to $+125^{\circ}C$	Inputs Open $V_{EE} = -4.2V$ to $-4.8V$ $V_{EE} = -4.2V$ to $-5.7V$	1, 2, 3	

Note 1: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals $-55^{\circ}C$), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

Note 2: Screen tested 100% on each device at $-55^{\circ}C$, $+25^{\circ}C$, and $+125^{\circ}C$, Subgroups 1, 2, 3, 7, and 8.

Note 3: Sample tested (Method 5005, Table I) on each manufactured lot at $-55^{\circ}C$, $+25^{\circ}C$, and $+125^{\circ}C$, Subgroups A1, 2, 3, 7, and 8.

Note 4: Guaranteed by applying specified input condition and testing V_{OH}/V_{OL} .

Military Version—Preliminary (Continued)**Ceramic Dual-In-Line Package AC Electrical Characteristics** $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -55^\circ C$		$T_C = +25^\circ C$		$T_C = +125^\circ C$		Units	Conditions	Notes
		Min	Max	Min	Max	Min	Max			
f_{Max}	Toggle Frequency	200		250		200		MHz	Figures 1 and 4	4
t_{PLH} t_{PHL}	Propagation Delay CP to Output	0.9	3.70	1.0	3.20	1.20	3.90	ns	Figures 1 and 4	1, 2, 3, 5
t_{PZH} t_{PHZ}	Propagation Delay OEN to Output	1.20	5.0	1.60	4.20	1.40	4.30	ns	Figures 3 and 7	1, 2, 3, 5
t_{TLH} t_{THL}	Transition Time 20% to 80%, 80% to 20%	0.40	2.50	0.40	2.40	0.40	2.70	ns	Figures 1 and 4	4
t_s	Setup Time D_n \overline{CEN} (Disable Time) \overline{CEN} (Release Time)	1.30 0.60 1.30		1.30 0.60 1.30		1.30 0.60 1.30		ns	Figures 2 and 5	4
t_h	Hold Time D_n	0.30		0.30		0.30		ns	Figures 1 and 6	4
$t_{pw(H)}$	Pulse Width HIGH CP	2.4		2.4		2.4		ns	Figures 1 and 4	4

Cerpak AC Electrical Characteristics $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -55^\circ C$		$T_C = +25^\circ C$		$T_C = +125^\circ C$		Units	Conditions	Notes
		Min	Max	Min	Max	Min	Max			
f_{Max}	Toggle Frequency	200		250		200		MHz	Figures 1 and 4	4
t_{PLH} t_{PHL}	Propagation Delay CP to Output	0.9	3.70	1.0	3.20	1.20	3.90	ns	Figures 1 and 4	1, 2, 3, 5
t_{PZH} t_{PHZ}	Propagation Delay OEN to Output	1.20	5.0	1.60	4.20	1.40	4.30	ns	Figures 3 and 7	1, 2, 3, 5
t_{TLH} t_{THL}	Transition Time 20% to 80%, 80% to 20%	0.40	2.50	0.40	2.40	0.40	2.70	ns	Figures 1 and 4	4
t_s	Setup Time D_n \overline{CEN} (Disable Time) \overline{CEN} (Release Time)	0.60 0.90 1.40		0.60 0.70 1.40		0.60 0.90 2.10		ns	Figures 2 and 5	4
t_h	Hold Time D_n	0.30		0.30		0.30		ns	Figures 1 and 6	4
$t_{pw(H)}$	Pulse Width HIGH CP	2.00		2.00		2.00		ns	Figures 1 and 4	4

Note 1: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals $-55^\circ C$), then testing immediately after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

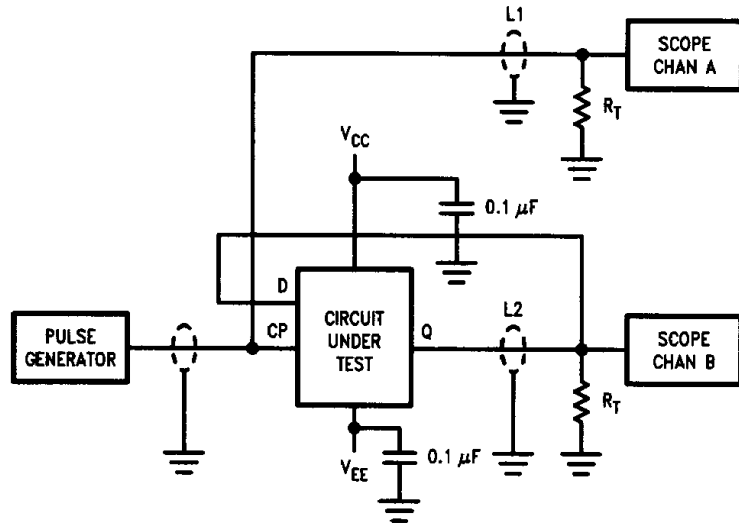
Note 2: Screen tested 100% on each device at $+25^\circ C$, temperature only, Subgroup A9.

Note 3: Sample tested (Method 5005, Table I) on each manufactured lot at $+25^\circ C$, Subgroup A9, and at $+125^\circ C$ and $-55^\circ C$ temperatures, Subgroups A10 and A11.

Note 4: Not tested at $+25^\circ C$, $+125^\circ C$, and $-55^\circ C$ temperature (design characterization data).

Note 5: The propagation delay specified is for single output switching. Delays may vary up to 300 ps with multiple outputs switching.

Test Circuitry

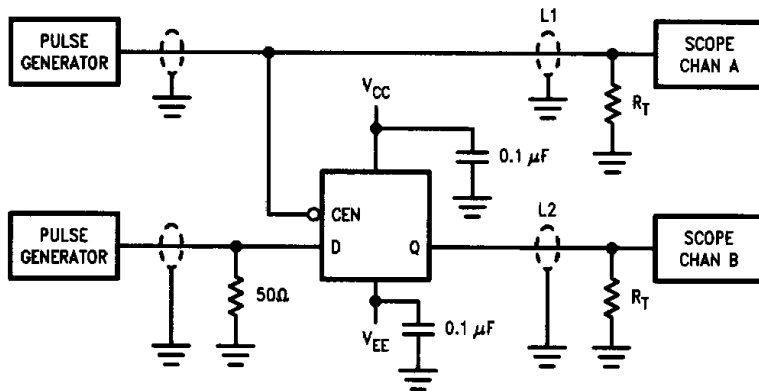


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FIGURE 1. Toggle Frequency Test Circuit

Notes:

- V_{CC}, V_{CCA} = +2V, V_{EE} = -2.5V
- L1 and L2 = equal length 50Ω impedance lines
- R_T = 50Ω terminator internal to scope
- Decoupling 0.1 μF from GND to V_{CC} and V_{EE}
- All unused outputs are loaded with 50Ω to GND
- C_L = Fixture and stray capacitance ≤ 3 pF

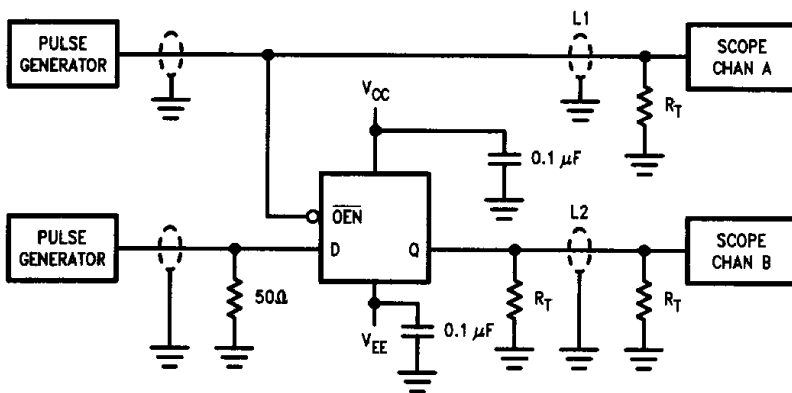


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FIGURE 2. AC Test Circuit

Notes:

- V_{CC}, V_{CCA} = +2V, V_{EE} = -2.5V
- L1 and L2 = equal length 50Ω impedance lines
- R_T = 50Ω terminator internal to scope
- Decoupling 0.1 μF from GND to V_{CC} and V_{EE}
- All unused outputs are loaded with 50Ω to GND
- C_L = Fixture and stray capacitance ≤ 3 pF



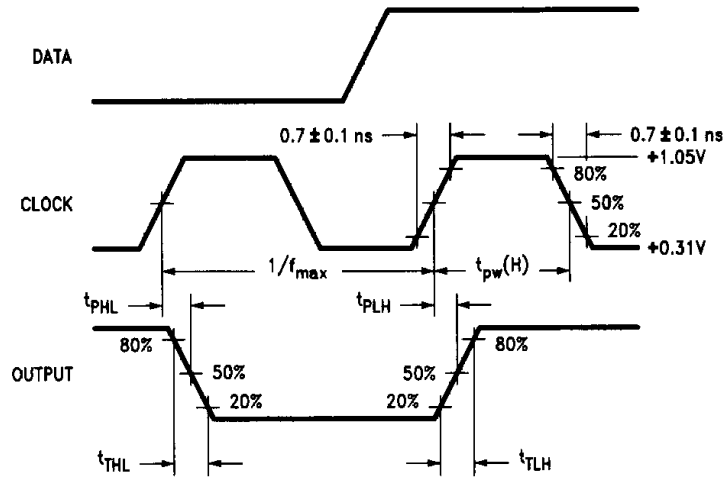
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FIGURE 3. AC Test Circuit

Notes:

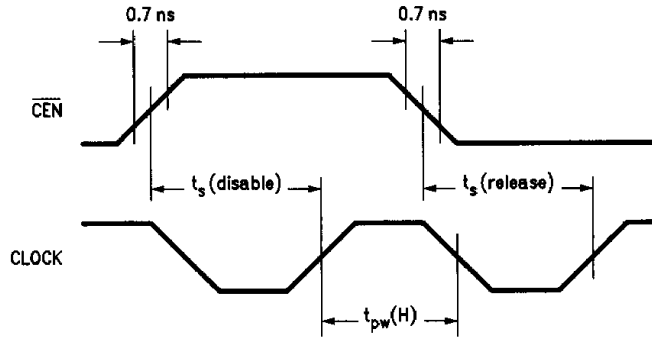
- V_{CC}, V_{CCA} = +2V, V_{EE} = -2.5V
- L1 and L2 = equal length 50Ω impedance lines
- R_T = 50Ω terminator internal to scope
- Decoupling 0.1 μF from GND to V_{CC} and V_{EE}
- All unused outputs are loaded with 50Ω to GND
- C_L = Fixture and stray capacitance ≤ 3 pF

Switching Waveforms



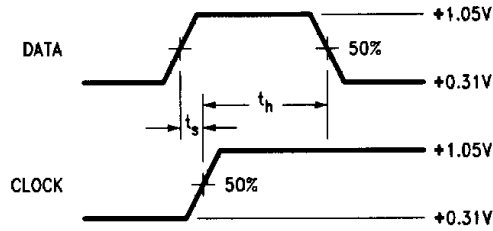
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FIGURE 4. Propagation Delay (Clock) and Transition Times



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FIGURE 5. Setup and Pulse Width Times

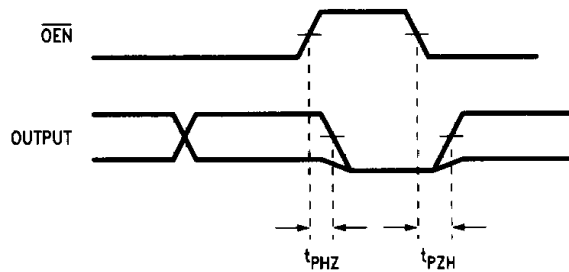


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FIGURE 6. Data Setup and Hold Time

Notes:

t_s is the minimum time before the transition of the clock that information must be present at the data input.
 t_h is the minimum time after the transition of the clock that information must remain unchanged at the data input.



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FIGURE 7. Cutoff Times